


<b>Search Notes</b>  	<b>Application/Control No.</b>  10829386	<b>Applicant(s)/Patent Under Reexamination</b>  AN ET AL.
	<b>Examiner</b>  Heyi, Henok G	<b>Art Unit</b>  2609

### SEARCHED

Class	Subclass	Date	Examiner
369	275.1 (text search only - see search history printout)	06/14/2007	Henok Heyi
720	719	06/19/2007	Henok Heyi

### SEARCH NOTES

Search Notes	Date	Examiner
Conducted both text and classified search and combination thereof using EAST. I have also used google search. Interference search has been done.	06/19/2007	Henok Heyi
Updated search and consulted with examiner Brian Miller, Primary Examiners Tan Dinh and William Korzuch	03/03/2008	Henok Heyi

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner